 ch Note	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/663,756	YQUEL ET AL.
Examiner	Art Unit
PHILIPPE S. DERAKSHANI	3754

SEARCHED			
Class	Subclass	Date	Examiner
222	402.2122 402.24	7/31/2006	PD

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
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